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## CRYSTALLIZATION OF CoFeB ELECTRODES IN MAGNETIC TUNNEL JUNCTIONS

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To establish relationship between crystallization of CoFeB electrodes and tunnel magnetoresistance (TMR), X-ray diffraction analysis (XRD) of pseudo spin valve (P-SV): Ta/Ru/Ta/CoFeB/MgO/CoFeB and exchange bias spin valve (EB-SV): Ta/Ru/Ta/PtMn/CoFe/Ru/CoFeB/MgO/CoFeB was performed.

It was found that the hexagonal Ru buffer layer is strongly textured in [002] direction with diffused Ta/Ru/Ta interfaces. The as-deposited paramagnetic PtMn layer was highly fcc (111)-oriented and transformed after annealing to antiferromagnetic fct (111)-oriented phase in EB-SV sample.

The CoFeB ferromagnetic electrodes were amorphous in as-deposited state and crystallized to bcc CoFe phase after annealing. The crystallization of annealed CoFeB electrodes in P-SV sample revealed stronger (002)-oriented texture than in EB-SV. We believe that due to this reason TMR ratio is significantly higher for P-SV junction (240 %) than for EB-SV (180 %).

Moreover, for P-SV and EB-SV junctions the bottom CoFeB electrode exhibited weaker (002)-oriented texture than the top electrode grown on highly (002)-oriented MgO. Importantly, the bottom electrode of EB-SV samples crystallize not only in [002] but also in [110] direction. Crystallization of CoFeB electrodes gave rise to increase of magnetization and magnetocrystalline anisotropy, and weak decrease in antiferromagnetic coupling of CoFe/Ru/CoFeB synthetic antiferrimagnet.

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